## ErAs/Semiconductor Nanocomposites for 1.55 µm-pumped and Hybrid Terahertz Photoconductive Switches

Angelique Gordon<sup>1</sup>, Wilder Acuna<sup>1</sup>, Weipeng Wu<sup>2</sup>, James Bork<sup>1</sup>, Matthew Doty<sup>1</sup>, Xi Wang<sup>1</sup>,

M. Benjamin Jungfleisch<sup>2</sup>, Lars Gundlach<sup>2,3</sup>, and Joshua M. O. Zide<sup>1</sup>

1 Department of Materials Science and Engineering, University of Delaware, Newark, Delaware 19716, USA

2 Department of Physics and Astronomy, University of Delaware, Newark, Delaware 19716, USA

3 Department of Chemistry and Biochemistry, University of Delaware, Newark, Delaware 19716, USA



[1] W. Acuna, et al., Adv. Funct. Mater. 34, 2041853, (2024).

**Figure 1:** Structural representation of  $ErAs:[(InGaBiAs)_x(InAlBiAs)_{1-x})]$  presenting the digital alloy period as well as the difference between co-deposition and interrupted growth techniques to incorporate ErAs.

**Figure 2:** Impact on ErAs:InGa(AlBi)As properties due to growth temperature and ErAs incorporation methods: co-deposition vs. interrupted growth. Altering ErAs growth techniques resulted in a four orders of magnitude reduction in carrier concentration and a similar increase in bulk resistivity [1].

**Figure 3:** Carrier dynamics measured by Optical Pump (800nm) THz probe spectroscopy demonstrating the fast decay time components in ErAs:InGaAlBiAs materials where sub-picosecond dynamics have been achieved [1]. (GT = Growth Temperature)

**Figure 4:** ErAs:InGaAlBiAs detector with fabricated bowtie-shaped photoconductive switch with a 10  $\mu$ m gap proof of concept results from (a) time domain THz spectroscopy mapping the THz pulse at different laser power levels, and (b) frequency domain, using a fast Fourier-transformed spectrum, showing broadband detection (0.1-1.1 THz) using 1550nm excitation [1].